

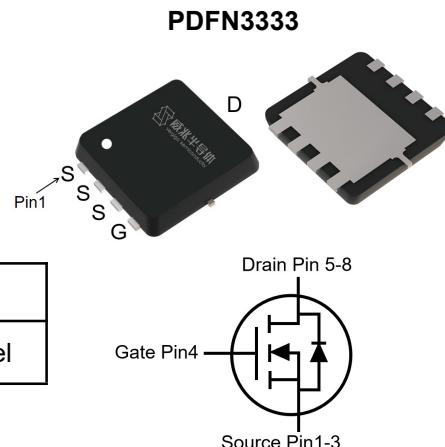
Features

- Enhancement mode
- VitoMOS® II Technology
- 100% Avalanche Tested, 100% R_g Tested

| | | |
|--|-----|----|
| V_{DS} | 100 | V |
| $R_{DS(on),TYP} @ V_{GS}=10\text{ V}$ | 100 | mΩ |
| $R_{DS(on),TYP} @ V_{GS}=4.5\text{ V}$ | 140 | mΩ |
| $I_D(\text{Silicon Limited})$ | 7.4 | A |



| Part ID | Package Type | Marking | Packing |
|----------|--------------|---------|--------------|
| VS1850GE | PDFN3333 | 1850GE | 5000PCS/Reel |



Maximum ratings, at $T_A = 25^\circ\text{C}$, unless otherwise specified

| Symbol | Parameter | Rating | Unit |
|----------------|--|---------------------------|------|
| $V(BR)DSS$ | Drain-Source breakdown voltage | 100 | V |
| V_{GS} | Gate-Source voltage | ± 20 | V |
| I_S | Diode continuous forward current (Silicon limited) | $T_c = 25^\circ\text{C}$ | A |
| I_D | Continuous drain current @ $V_{GS}=10\text{V}$ (Silicon limited) | $T_c = 25^\circ\text{C}$ | A |
| I_D | Continuous drain current @ $V_{GS}=10\text{V}$ (Silicon limited) | $T_c = 100^\circ\text{C}$ | A |
| I_{DM} | Pulse drain current tested ① | $T_c = 25^\circ\text{C}$ | A |
| I_{DSM} | Continuous drain current @ $V_{GS}=10\text{V}$ | $T_A = 25^\circ\text{C}$ | A |
| | | $T_A = 70^\circ\text{C}$ | A |
| EAS | Maximum Avalanche energy, single pulsed ② | 0.64 | mJ |
| P_D | Maximum power dissipation ③ | $T_c = 25^\circ\text{C}$ | W |
| | | $T_c = 100^\circ\text{C}$ | W |
| P_{DSM} | Maximum power dissipation ④ | $T_A = 25^\circ\text{C}$ | W |
| | | $T_A = 70^\circ\text{C}$ | W |
| T_J, T_{STG} | Operating Junction and Storage Temperature Range | -55 to 150 | °C |

Thermal Characteristics

| Symbol | Parameter | Typical | Max | Unit |
|-----------------|---|---------|-----|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case ⑤ | 7.7 | 9.2 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient ⑥ | 46 | 55 | °C/W |

Electrical Characteristics

| Symbol | Parameter | Condition | Min. | Typ. | Max. | Unit |
|---|---|--|------|------|-----------|------------------|
| Static Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise stated) | | | | | | |
| V(BR)DSS | Drain-Source Breakdown Voltage | $V_{GS}=0\text{V}, I_D=250\mu\text{A}$ | 100 | -- | -- | V |
| IDSS | Zero Gate Voltage Drain Current($T_j=25^\circ\text{C}$) | $V_{DS}=100\text{V}, V_{GS}=0\text{V}$ | -- | -- | 1 | μA |
| | Zero Gate Voltage Drain Current($T_j=125^\circ\text{C}$) ^⑦ | $V_{DS}=100\text{V}, V_{GS}=0\text{V}$ | -- | -- | 100 | μA |
| IGSS | Gate-Body Leakage Current | $V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$ | -- | -- | ± 100 | nA |
| VGS(th) | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu\text{A}$ | 1.3 | 1.8 | 2.4 | V |
| RDS(on) | Drain-Source On-State Resistance ^⑧ | $V_{GS}=10\text{V}, I_D=5\text{A}$ | -- | 100 | 130 | $\text{m}\Omega$ |
| | | ($T_j=100^\circ\text{C}$) ^⑦ | -- | 150 | -- | $\text{m}\Omega$ |
| RDS(on) | Drain-Source On-State Resistance ^⑧ | $V_{GS}=4.5\text{V}, I_D=2\text{A}$ | -- | 140 | 180 | $\text{m}\Omega$ |
| Dynamic Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (unless otherwise stated) | | | | | | |
| Ciss | Input Capacitance ^⑦ | $V_{DS}=50\text{V}, V_{GS}=0\text{V}, f=100\text{KHz}$ | -- | 160 | -- | pF |
| Coss | Output Capacitance ^⑦ | | -- | 45 | -- | pF |
| Crss | Reverse Transfer Capacitance ^⑦ | | -- | 5 | -- | pF |
| Rg | Gate Resistance | f=1MHz | -- | 1.9 | -- | Ω |
| Qg(10V) | Total Gate Charge ^⑦ | $V_{DS}=50\text{V}, I_D=5\text{A}, V_{GS}=10\text{V}$ | -- | 3.9 | -- | nC |
| Qg(4.5V) | Total Gate Charge ^⑦ | | -- | 2 | -- | nC |
| Qgs | Gate-Source Charge ^⑦ | | -- | 0.9 | -- | nC |
| Qgd | Gate-Drain Charge ^⑦ | | -- | 1 | -- | nC |
| Switching Characteristics ^⑦ | | | | | | |
| Td(on) | Turn-on Delay Time | $V_{DD}=50\text{V}, I_D=5\text{A}, R_G=3\Omega, V_{GS}=10\text{V}$ | -- | 3.2 | -- | ns |
| Tr | Turn-on Rise Time | | -- | 2.8 | -- | ns |
| Td(off) | Turn-Off Delay Time | | -- | 6.4 | -- | ns |
| Tf | Turn-Off Fall Time | | -- | 1.6 | -- | ns |
| Source- Drain Diode Characteristics@ $T_j = 25^\circ\text{C}$ (unless otherwise stated) | | | | | | |
| VSD | Forward on voltage | $I_{SD}=5\text{A}, V_{GS}=0\text{V}$ | -- | 0.95 | 1.2 | V |
| Trr | Reverse Recovery Time ^⑦ | $V_{DD}=50\text{V}, I_{SD}=5\text{A}, V_{GS}=0\text{V}$ $dI/dt=100\text{A}/\mu\text{s}$ | -- | 39 | -- | ns |
| Qrr | Reverse Recovery Charge ^⑦ | | -- | 18 | -- | nC |

NOTE:

- ① Single pulse; pulse width $\leq 100\mu\text{s}$.
- ② This maximum value is based on starting $T_j = 25^\circ\text{C}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 1.6\text{A}$, $V_{GS} = 10\text{V}$; 100% FT tested at $L = 0.5\text{mH}$, $I_{AS} = 1.1\text{A}$.
- ③ The power dissipation P_d is based on $T_j(\text{max})$, using junction-to-case thermal resistance $R_{\theta JC}$.
- ④ The power dissipation P_{dsm} is based on $T_j(\text{max})$, using junction-to-ambient thermal resistance $R_{\theta JA}$.
- ⑤ These tests are performed respectively with the device mounted on a 1 in2 pad and a minimum pad of 2oz. Copper FR-4 board in a still air environment with $TA=25^\circ\text{C}$, using Transient Dual Interface method to acquire $R_{\theta JC}$.
- ⑥ These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with $TA=25^\circ\text{C}$.
- ⑦ Guaranteed by design, not subject to production testing.
- ⑧ Pulse width $\leq 380\mu\text{s}$; duty cycles 2%.

Typical Characteristics

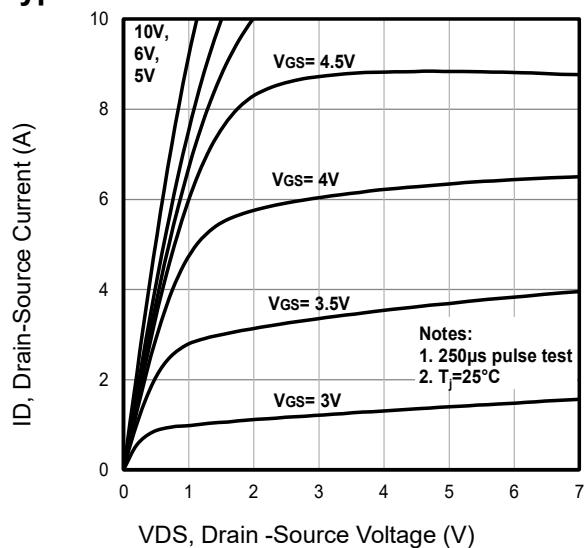


Fig1. Typical Output Characteristics

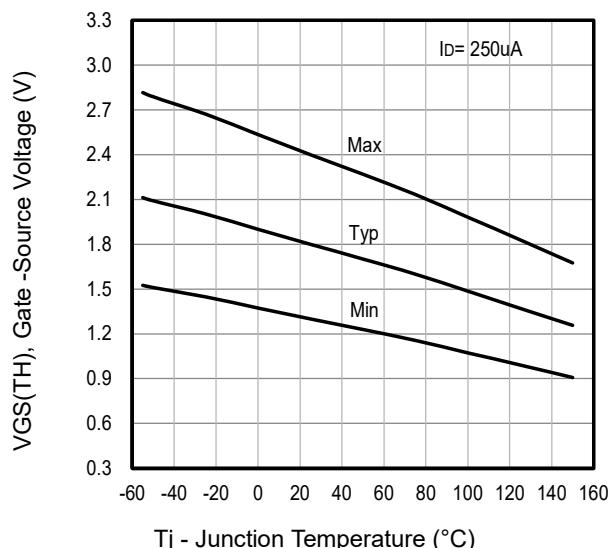


Fig2. Typical $V_{GS(TH)}$ Gate -Source Voltage Vs. T_j

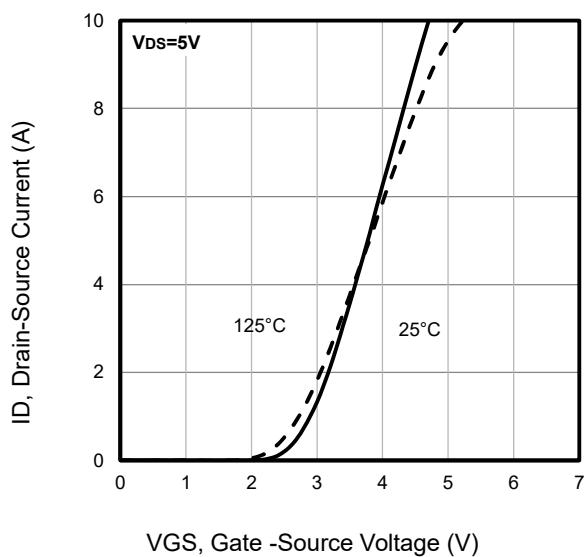


Fig3. Typical Transfer Characteristics

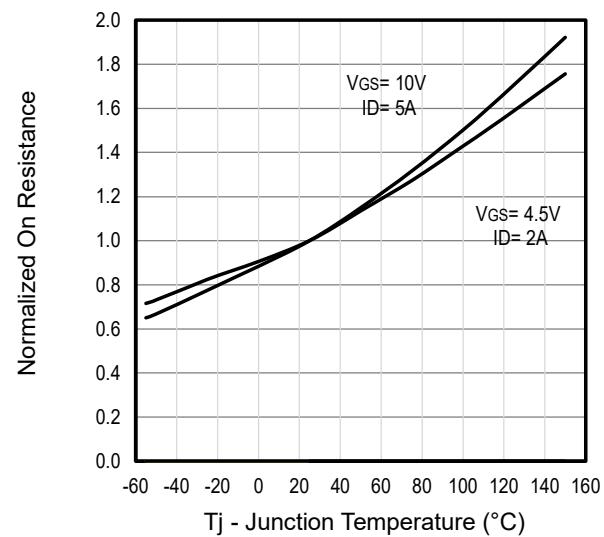


Fig4. Typical Normalized On-Resistance Vs. T_j

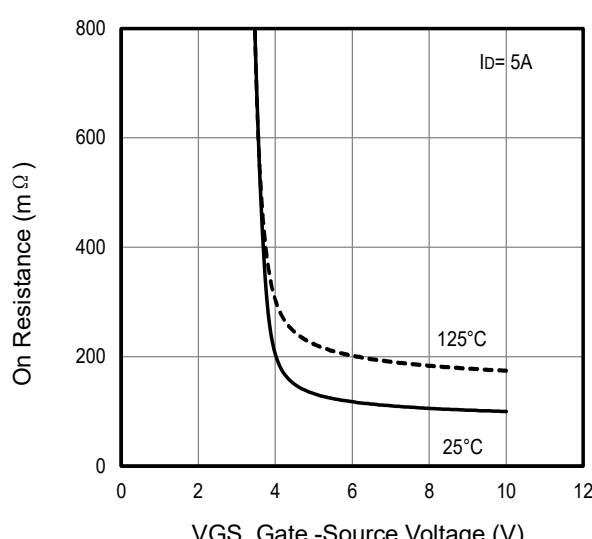


Fig5. Typical On Resistance Vs Gate -Source Voltage

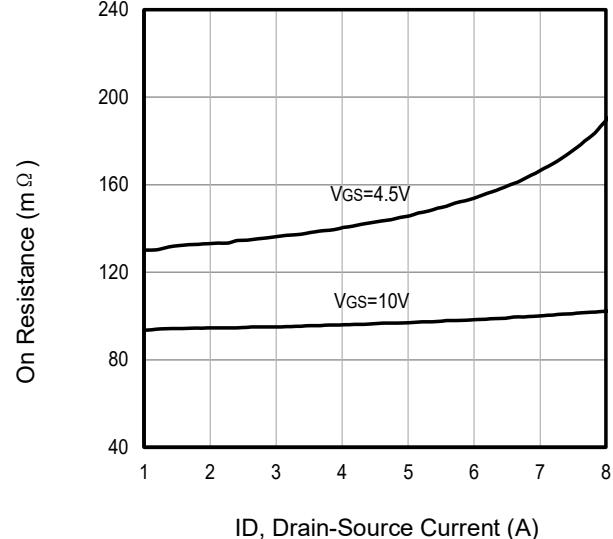


Fig6. Typical On Resistance Vs Drain Current

Typical Characteristics

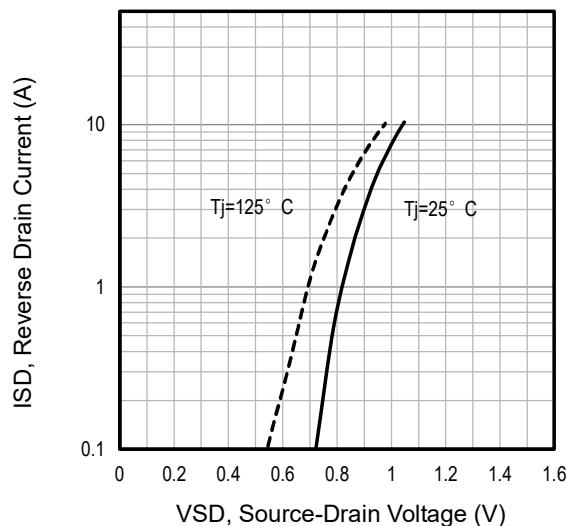


Fig7. Typical Source-Drain Diode Forward Voltage

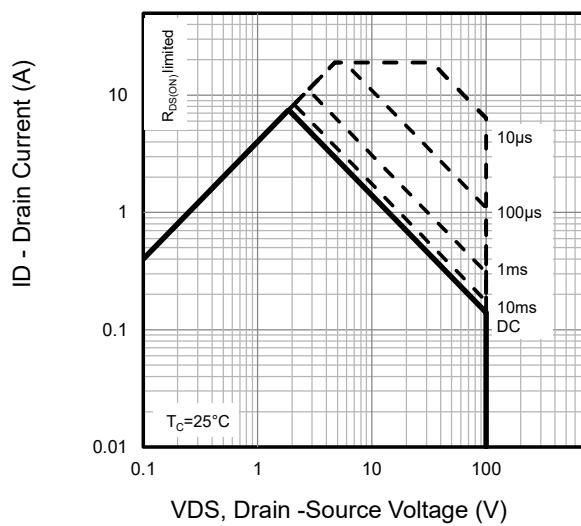


Fig8. Maximum Safe Operating Area

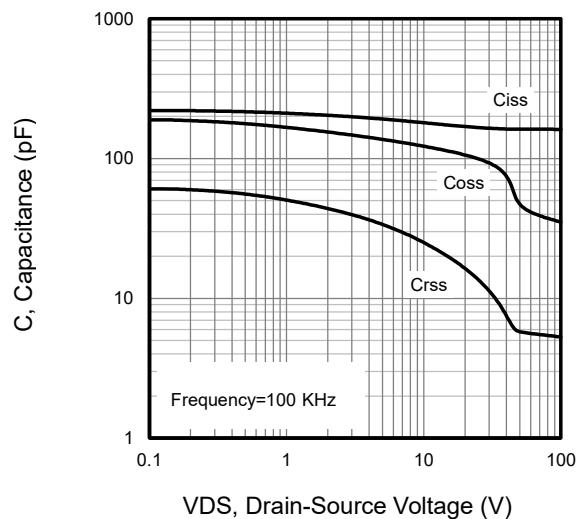


Fig9. Typical Capacitance Vs. Drain-Source Voltage

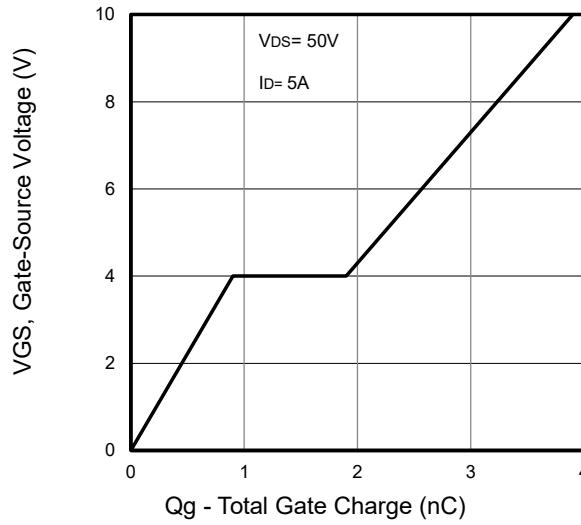


Fig10. Typical Gate Charge Vs. Gate-Source Voltage

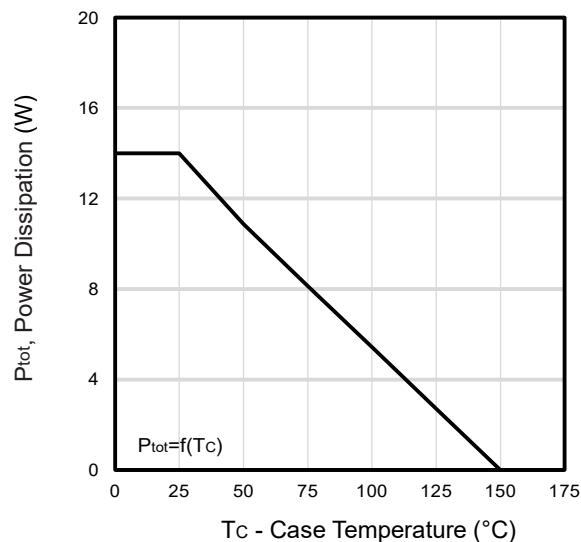


Fig11. Power Dissipation Vs. Case Temperature

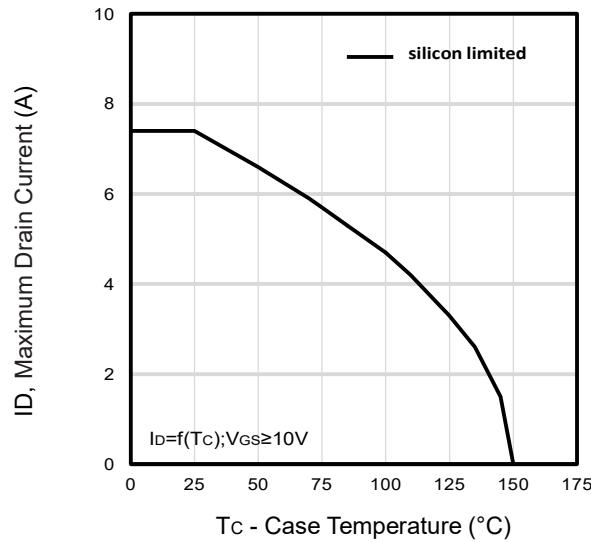


Fig12. Maximum Drain Current Vs. Case Temperature

Typical Characteristics

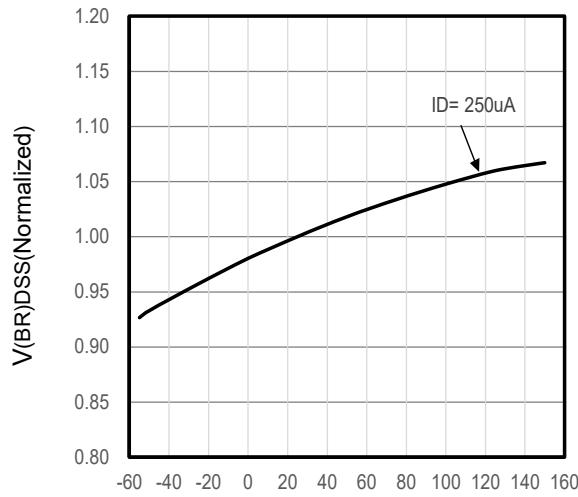


Fig13. Typical V(BR)DSS Vs T_j

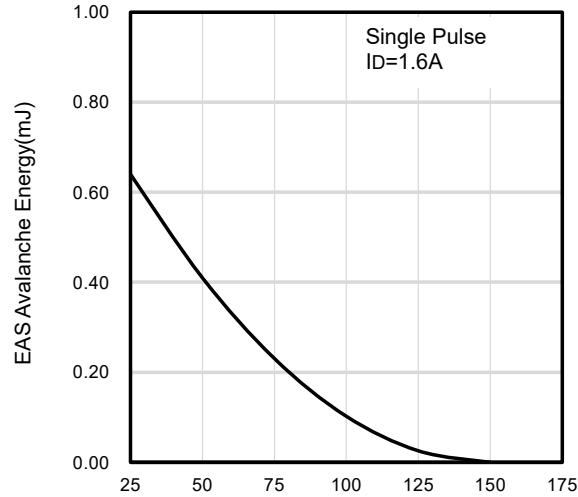


Fig14. Maximum Avalanche Energy vs Temperature (°C)

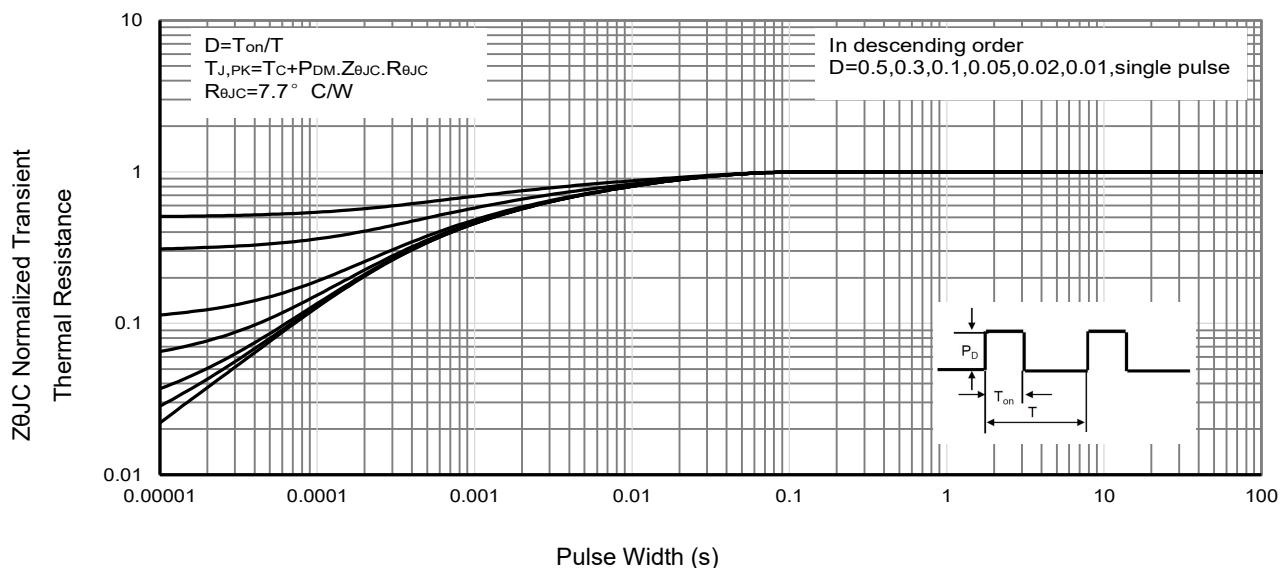


Fig15 . Normalized Maximum Transient Thermal Impedance

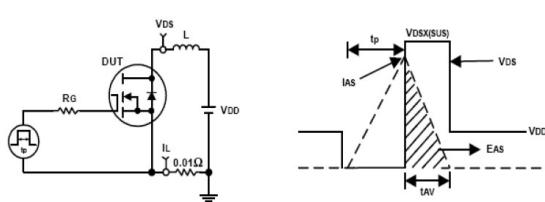


Fig16. Unclamped Inductive Test Circuit and waveforms

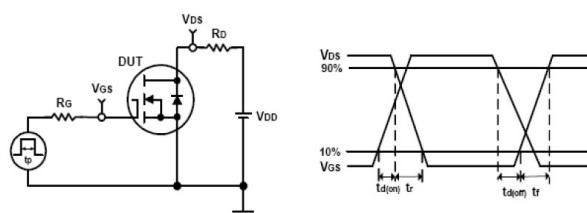
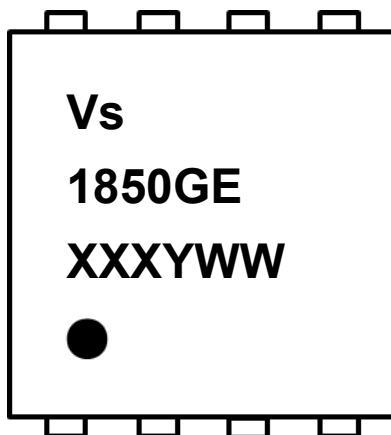


Fig17. Switching Time Test Circuit and waveforms

Marking Information

 1st line: Vergiga Code (Vs)

 2nd line: Part Number (1850GE)

 3rd line: Date code (XXXYWW)

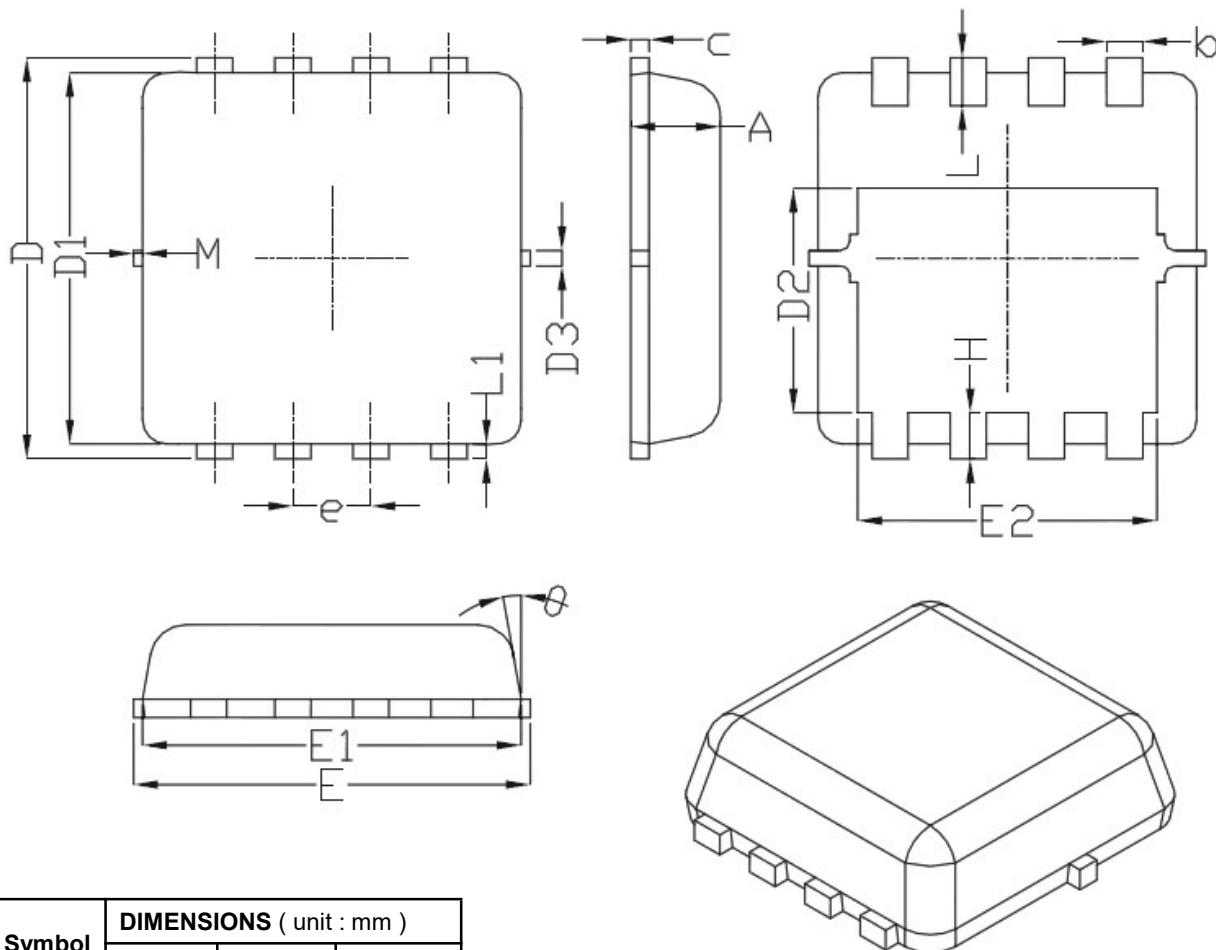
XXX: Wafer Lot Number Code , code changed with Lot Number

Y: Year Code , refer to table below

WW: Week Code (01 to 53)

| Code | C | D | E | F | G | H | J | K | L | M | N | P | Q | R | S | T |
|------|------|------|------|------|------|------|------|------|------|------|------|------|------|------|------|------|
| Year | 2015 | 2016 | 2017 | 2018 | 2019 | 2020 | 2021 | 2022 | 2023 | 2024 | 2025 | 2026 | 2027 | 2028 | 2029 | 2030 |

PDFN3333 Package Outline Data



| Symbol | DIMENSIONS (unit : mm) | | |
|-----------------|--------------------------|------|------|
| | Min | Typ | Max |
| A | 0.70 | 0.75 | 0.80 |
| b | 0.25 | 0.30 | 0.35 |
| C | 0.10 | 0.15 | 0.25 |
| D | 3.25 | 3.35 | 3.45 |
| D1 | 3.00 | 3.10 | 3.20 |
| D2 | 1.78 | 1.88 | 1.98 |
| D3 | -- | 0.13 | -- |
| E | 3.00 | 3.20 | 3.40 |
| E1 | 3.00 | 3.10 | 3.20 |
| E2 | 2.39 | 2.49 | 2.59 |
| e | 0.65 BSC | | |
| H | 0.30 | 0.39 | 0.50 |
| L | 0.30 | 0.40 | 0.50 |
| L1 | -- | 0.13 | -- |
| θ | -- | 10° | 12° |
| M | * | * | 0.15 |
| * Not specified | | | |

Notes:

1. Follow JEDEC MO-240 variation CA.
2. Dimensions "D1" and "E1" do NOT include mold flash protrusions or gate burrs.
3. Dimensions "D1" and "E1" include interterminal flash or protrusion. Interterminal flash or protrusion shall not exceed 0.25mm per side.